

HRDP6 Oral Program

Monday 27 June 2011

Chair : Daewon Moon

9h00	I 1	Gustafsson	<i>Medium Energy Ion Scattering from Novel Materials: High-k, SiC, Oxide Interfaces and Topological Insulators.</i>
9h35	O1	Primetzhoffer	High resolution Rutherford backscattering spectrometry: Depth profiling and composition analysis.
10h00	O2	Bauer	Information depth in Low Energy Ion Scattering

Coffee

Chair : Denis Jalabert

10h45	I 2	Shutthanandan	<i>High resolution depth profile analysis of interface mixing at the LaAlO₃/SrTiO₃ interface</i>
11h20	O3	Munnik	High-resolution RBS investigation of LaLuO ₃ as candidate for a second-generation high-k material
11h45	O4	Chan	High-resolution Rutherford Backscattering Spectrometry investigation of solid phase epitaxial growth in Sn-implanted Si

Lunch

Chair : John O'Connor

14h00	I 3	Blavette	<i>Ultimate depth profiling using Atom Probe Tomography</i>
14h35	O5	Shuttanandan	Embedded Nanoparticle Analysis using Atom Probe Tomography and High-Resolution Electron Microscopy
15h00	O6	King	Surface Analysis of Samples Returned from the NASA Genesis Mission

Coffee

Posters and Sponsor Displays

Tuesday 28 June 2011

Chair : Kenji Kimura

09h00	I 4	Goncharova	<i>Transport and exchange of hydrogen and oxygen isotopes using medium energy ion scattering</i>
09h35	O7	Deokar	Investigation of oxygen exchange between CO ₂ and thermally grown SiO ₂ network by Narrow Resonance Depth Profiling
10h00	O8	Py	Ultimate backside sample preparation for ultra thin high-k/metal gate stack depth profiling with ToF-SIMS, MEIS and pAR-XPS

Coffee

Chair : Pedro Grande

10h45	I 5	Visikovskiy	<i>Oxygen deficiency and excess of metal-oxide surfaces analyzed by MEIS and ERD</i>
11h20	O9	Woodruff	The V ₂ O ₃ (0001) surface termination crystallography: phase equilibrium revealed by medium- and low-energy ion scattering.
11h45	O10	Jalabert	Strain measurement in a thin silicon film using Medium Energy Ion Scattering.

Lunch

Chair : Lyudmila Goncharova

14h00	I 6	Etgens	<i>Layer-by-layer film growth monitored by Grazing Incidence Fast Atom Diffraction</i>
14h35	O11	Brongersma	Quantitative and non-destructive determination of the atomic composition of the outer surface and of in-depth profiles by HS-LEIS
15h00	O12	Goebel	Quantification of second layer contributions in Low Energy Ion Scattering

Coffee

Tuesday 28 June 2011(continued)

Chair : Peter Bauer

15h45	I7	Noakes	<i>Dealing with disorder, defects and amorphicity in medium energy ion scattering experiments</i>
16h20	O13	Bergmaier	Monte Carlo simulations of high resolution elastic recoil detection depth profiles
16h45	O14	Ganem	Vicinage Effect and Coulomb explosion dynamics of hydrogen molecules in Silicon Nitride Films
17h10	O15	Hentz	A simple approach for simulating the 2D MEIS spectrum in crystalline materials

Wednesday 29 June 2011

Chair : Bruce King

09h00	I8	Vandervorst	<i>High Resolution SIMS Depth Profiling</i>
09h35	O16	Ngo	Depth profiling of metal - organic samples by (low-energy) dynamic SIMS
10h00	O17	Meerschaut	Compositional analysis of NiO thin films grown by MOCVD

Coffee

Chair : Wilfried Vandervorst

10h45	I9	Sánchez	<i>Adsorption and thermal stability of organic films on surfaces monitored by Direct Recoil Spectroscopy</i>
11h20	O18	Itani	Depth Resolution in SIMS Depth Profiling with Oxygen Primary Ions
11h45	O19	Galtayries	ToF-SIMS depth profiling of nanometric Mg/Co/Zr stacks

Lunch

Outing

Gala Dinner

Thursday 30 June 2011

Chair : Phil Woodruff

09h00	I10	Baddeley	<i>Using MEIS to probe segregation effects in bimetallic nanoparticles.</i>
09h35	O20	Sortica	Nanostructures characterization using the MEIS technique.
10h00	O21	Sanchez	Structural characterization of buried nanostructured materials through Medium Energy Ion Scattering technique

Coffee

Chair : Torgny Gustafsson

10h45	I11	Kimura	<i>Improvement of sensitivity in high-resolution RBS by reducing detector noise</i>
11h20	O22	Bailey	A UHV-compatible, demountable heat transfer system.
11h45	O23	Moon	Development of imaging TOF- MEIS and Applications

Closing Remarks

Lunch

END